

# IDENTIFICATION DU SYSTÈME D'ACQUISITION SCANNER X À PARTIR DE L'ANALYSE DU BRUIT DANS DES IMAGES MÉDICALES

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# Context

- Medical image stored as a DICOM file:  
**meta data + image content**
  - Meta data may be distorted, modified or lost.
  - Image content may be falsified modified (e.g. mixing different images)
- Authentication of the acquisition device in medical image by noise analyzing



**CT-Scanner**



**2D Slice**

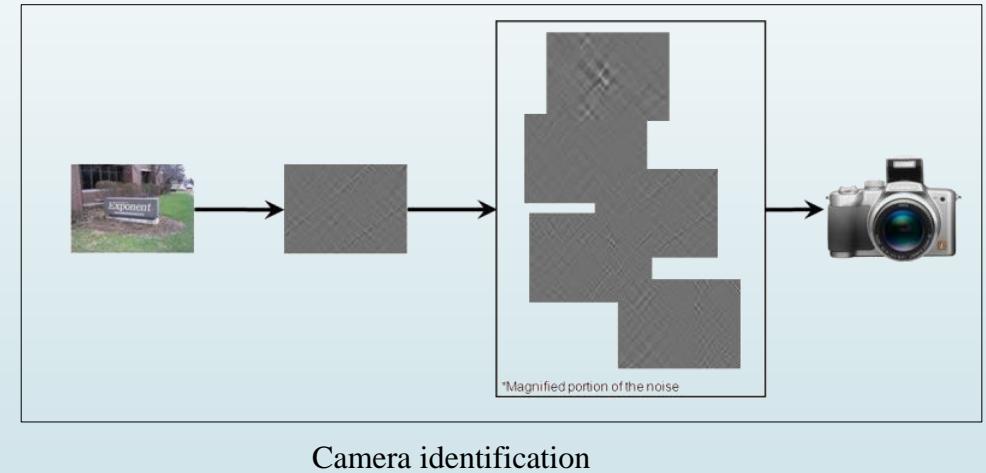
[\*] Jerry T. Bushberg, J. Anthony Seibert, Edwin M. Leidholdt Jr., and John M. Boone, The Essential Physics of Medical Imaging, Third Edition, LWW, third, north american edition edition, 12 2011.

[\*] Klaus D. Toennies, Guide to Medical Image Analysis - Methods and Algorithms, Advances in Computer Vision and Pattern Recognition. Springer, 2012.

# Context

Digital image forensics:

- Forgeries tracing
  - [1] General digital photography
  - [2] Digital blind forensics
- Device identification
  - [3] Digital camera identification
  - [4] Medical image characteristics
  - [5] Identification of digital radiography images



[1] H. T. Sencar and N. Memon, *Digital Image Forensics: There is More to a Picture Than Meets the Eye*, Springer, 2013.

[2] H. Huang, G. Coatrieux, H. Shu, L. Luo, and C. Roux, "Blind integrity verification of medical images," *IEEE Transactions on Information Technology in Biomedicine*, vol. 16, no. 6, pp. 1122–1126, 2012.

[3] J. Lukas, J. Fridrich, and M. Goljan, "Digital camera identification from sensor pattern noise," *IEEE Transactions on Information Forensics and Security*, vol. 1, no. 2, pp. 205–214, 2006.

[4] J. B. Solomon, O. Christianson, and E. Samei, "Quantitative comparison of noise texture across CT scanners from different manufacturers," *Medical physics*, vol. 39, no. 10, pp. 6048–55, October 2012.

[5] Y. Duan, G. Coatrieux and H. Shu, "Identification of digital radiography image source based on digital radiography pattern noise recognition" *IEEE ICIP 2014*, pp. 5372-5376, Paris, France.

4



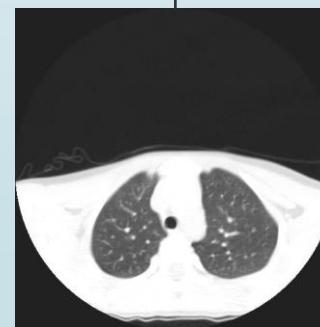
CT-Scanner 1

CT-Scanner 2

CT-Scanner 3

CT-Scanner n

Problem



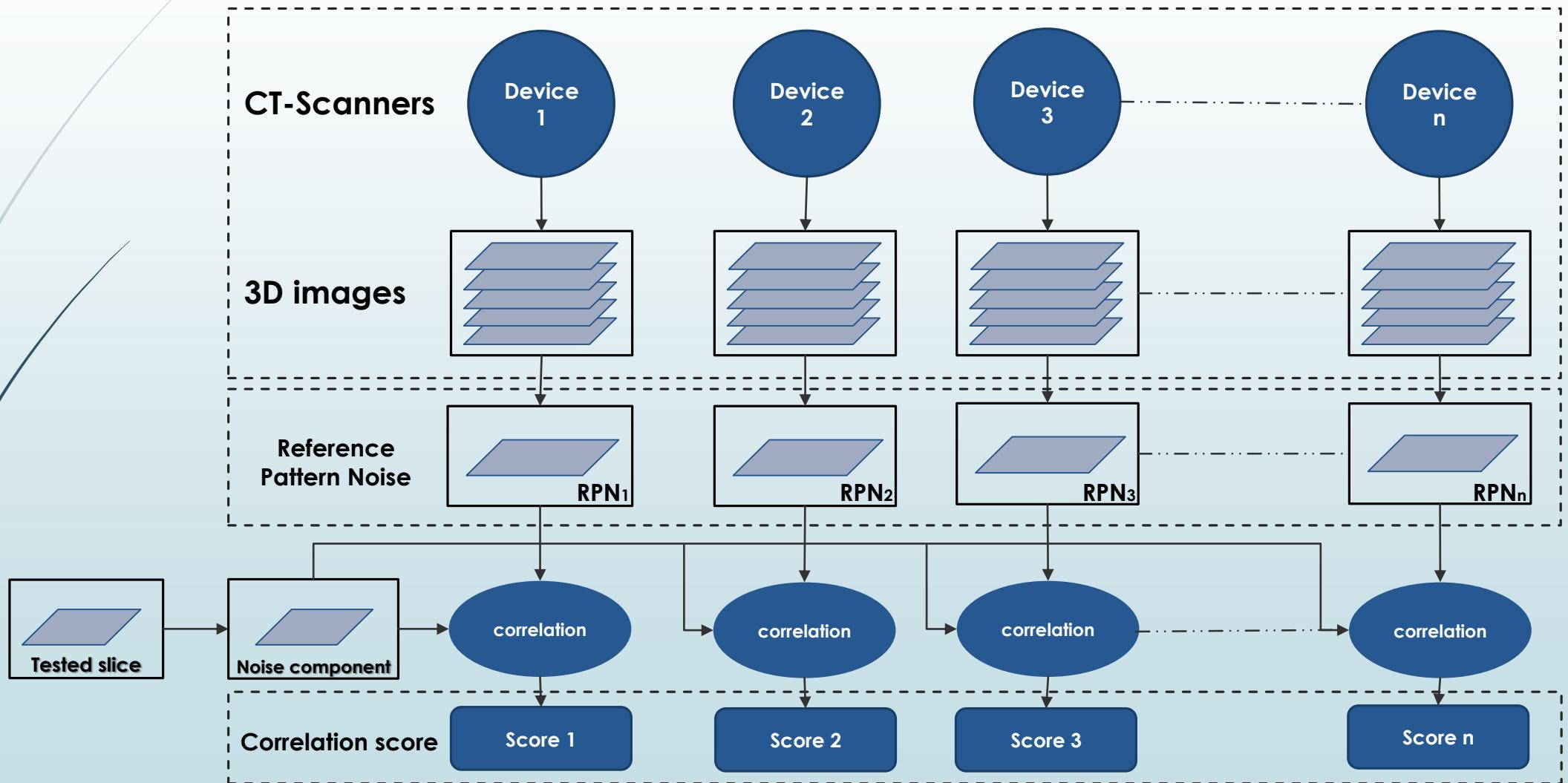
2D Slice

Proposed method

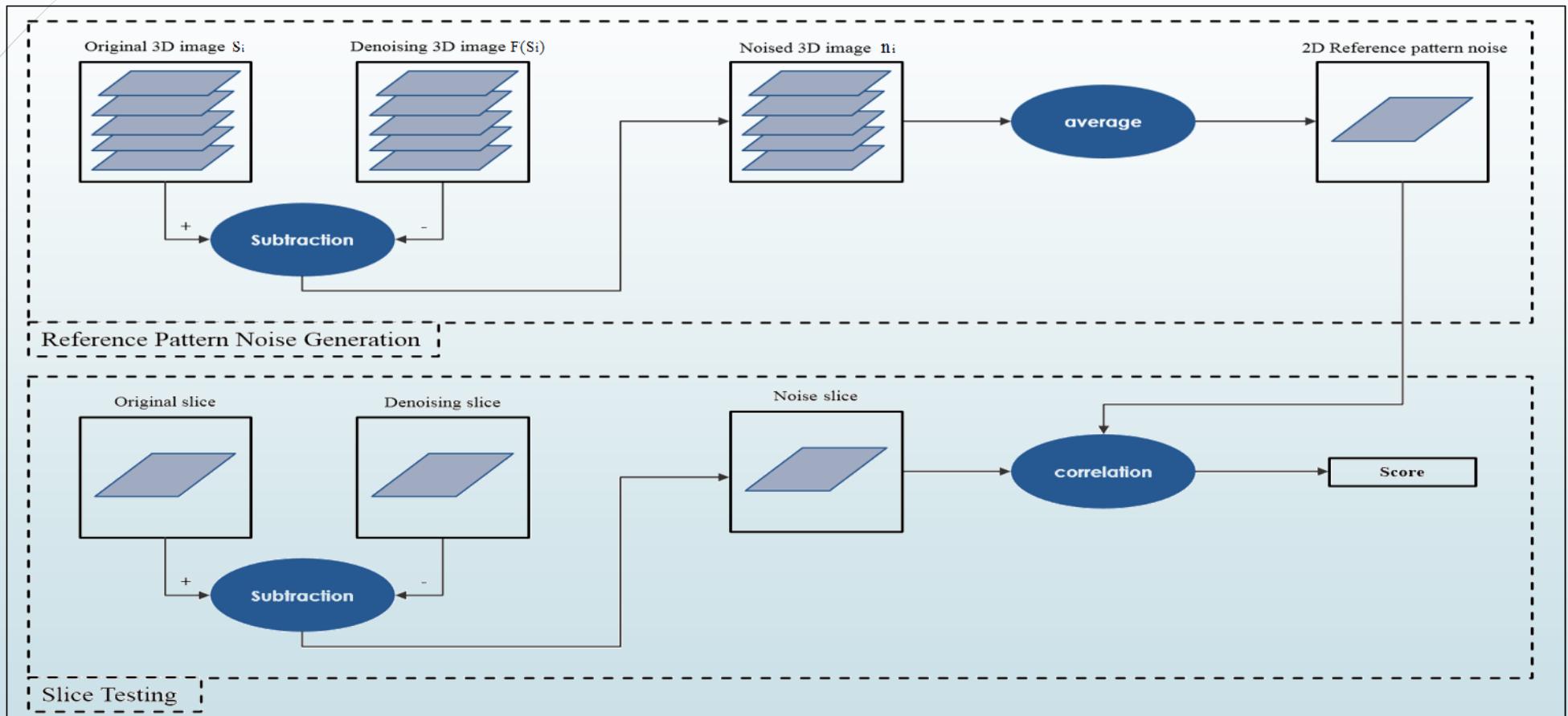
# Outlines

- Context
- Presentation of the identification method
- Experimental results
- Conclusion and future work

# Identification method

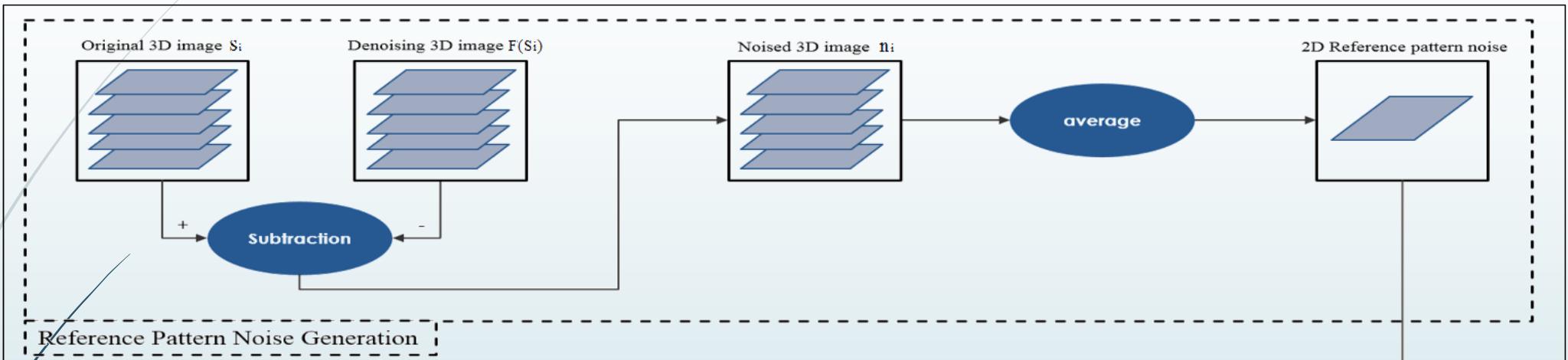


# For each device



J. Lukas, J. Fridrich, and M. Goljan, "Digital camera identification from sensor pattern noise," IEEE Transactions on Information Forensics and Security, vol. 1, no. 2, pp. 205–214, 2006.

# RPN Generation



1. Extract the reference pattern noise

$$n^{(i)} = s^{(i)} - F(s^{(i)})$$

**n**: noise component

**s**: slice

**F()**: denoising function

**i**: slice number

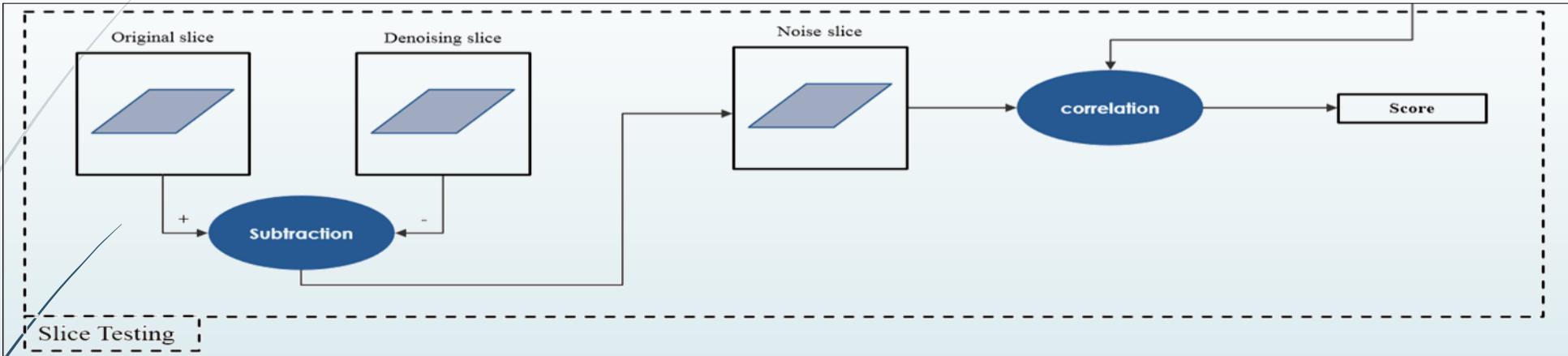
$$RPN = \frac{1}{N} \sum_{i=1}^N n^{(i)}$$

**RPN**: reference pattern noise

**N**: number of noise slices

**n**: noise component

# Noise extraction



2. Extract the noise component for the tested slice

$$n = s - F(s)$$

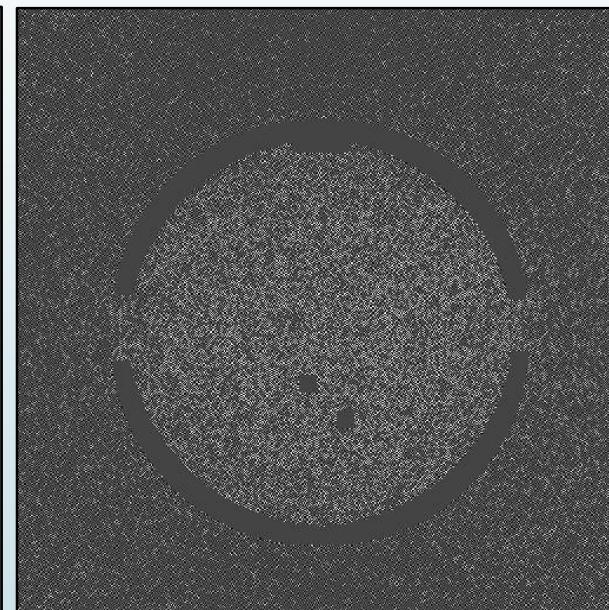
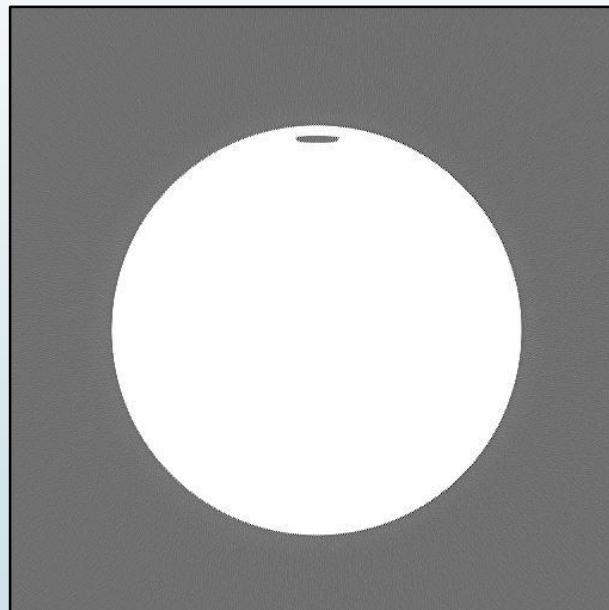
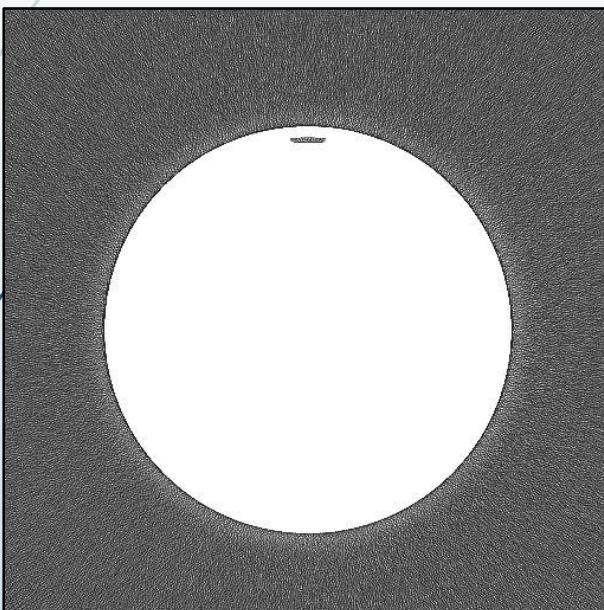
**n**: noise component

**s**: slice

**F()**: denoising function

# Noise extraction

Extract the noise component



Example: a) Original slice from a Siemens device, b) Its denoised component, c) The noise component

# Denoising algorithm

1. Four levels of wavelet decomposition.
2. Denote the vertical, horizontal, and diagonal subbands as

$$h(i, j), v(i, j), d(i, j)$$

3. Estimate the local variance for each wavelet coefficient for 4 sizes of a square  $W \times W$  neighborhood  $N$ , for  $W \in \{3, 5, 7, 9\}$ .

$$\hat{\sigma}_w^2(i, j) = \max \left( 0, \frac{1}{W^2} \sum_{(i,j) \in N} h^2(i, j) - \sigma_0^2 \right), (i, j) \in J.$$

4. Take the minimum of the 4 variances as the final estimate

$$\hat{\sigma}^2(i, j) = \min \left( \sigma_3^2(i, j), \sigma_5^2(i, j), \sigma_7^2(i, j), \sigma_9^2(i, j) \right), (i, j) \in J.$$

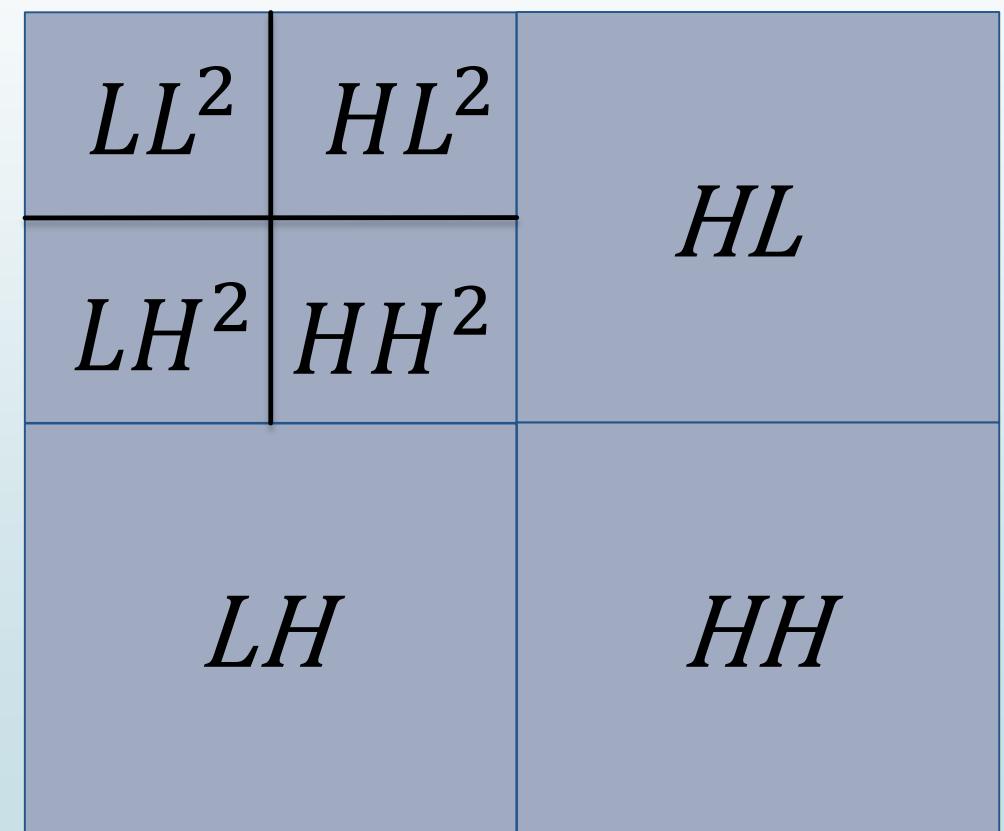
5. Denoised wavelet coefficients using the Wiener filter

$$h_{\text{den}}(i, j) = h(i, j) \frac{\hat{\sigma}^2(i, j)}{\hat{\sigma}^2(i, j) + \sigma_0^2}$$

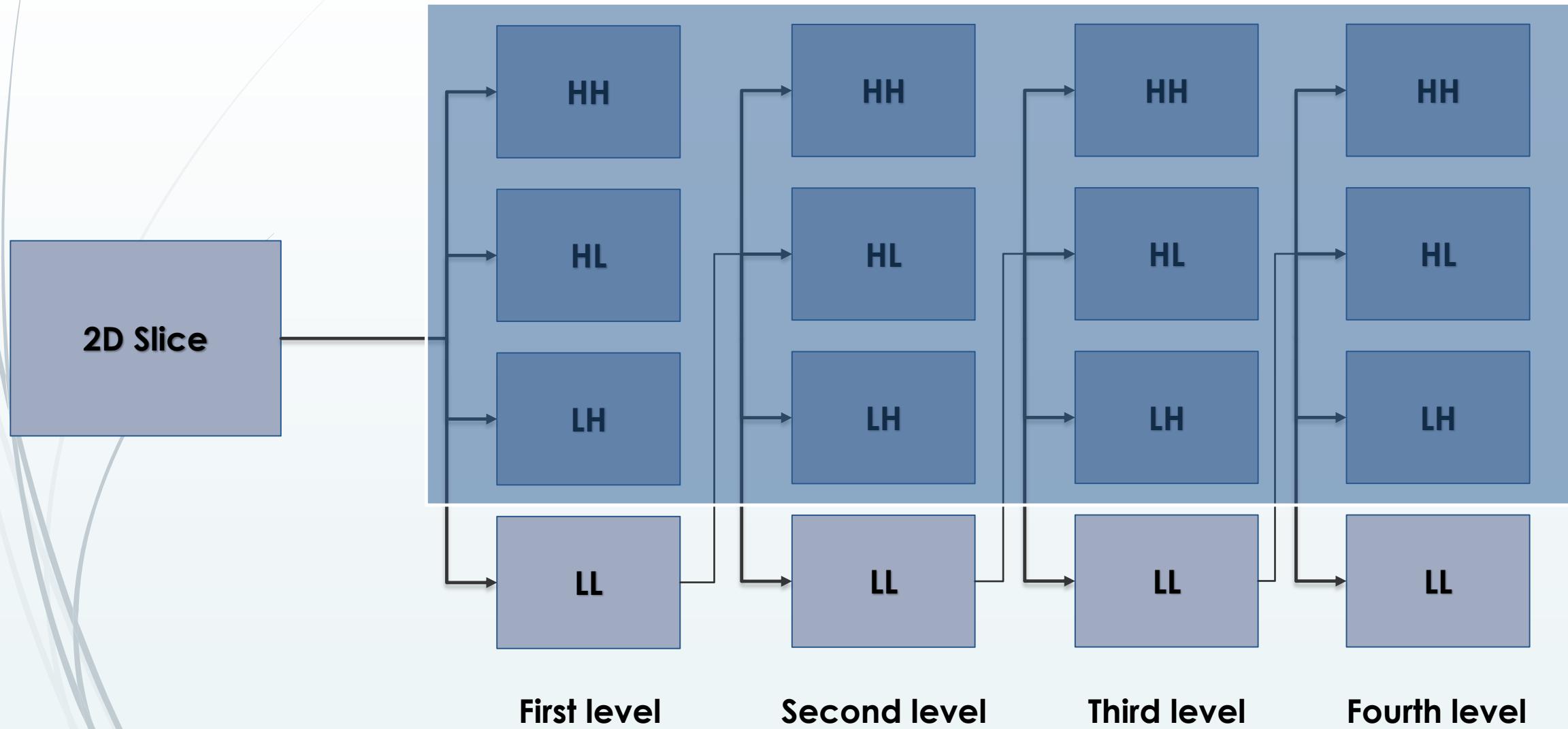
6. Apply the inverse wavelet transform to the denoised wavelet coefficients.

# Wavelet Decomposition

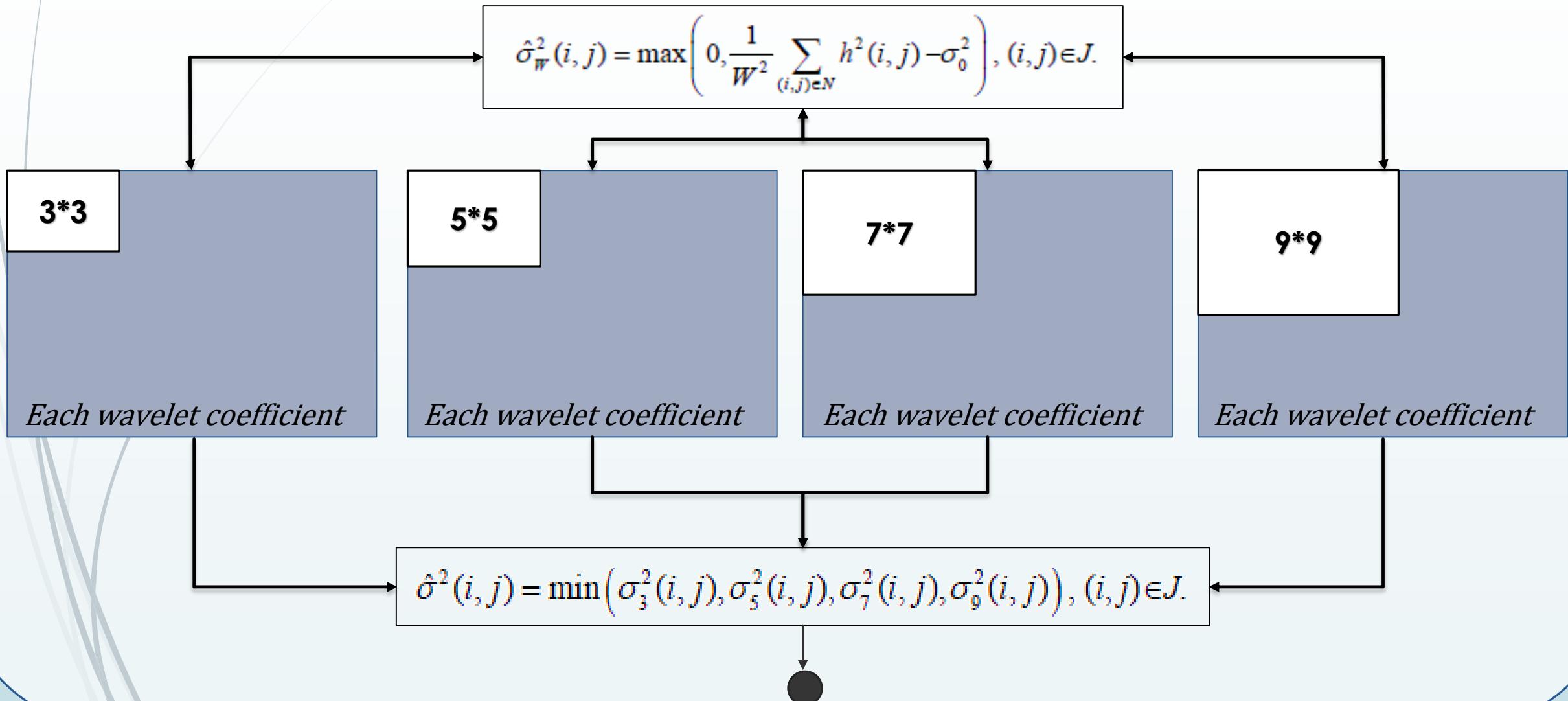
- Example of two levels of wavelet decomposition



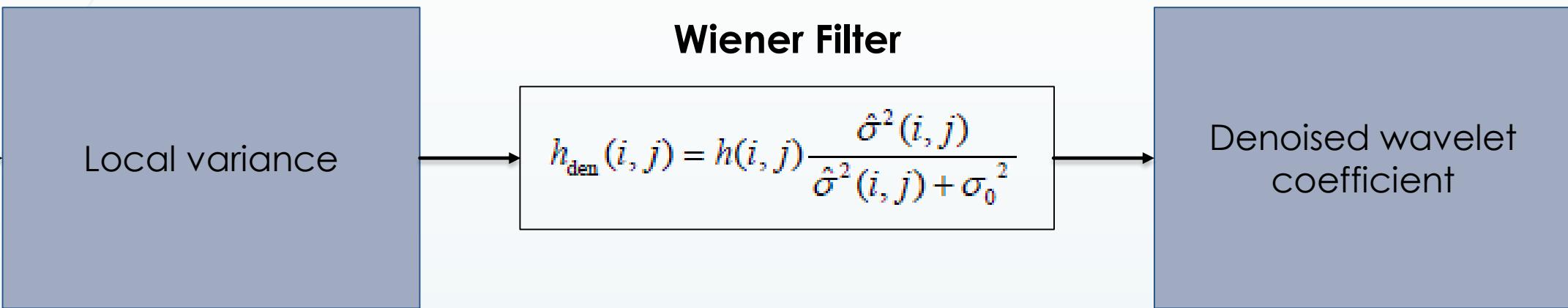
# Wavelet Levels



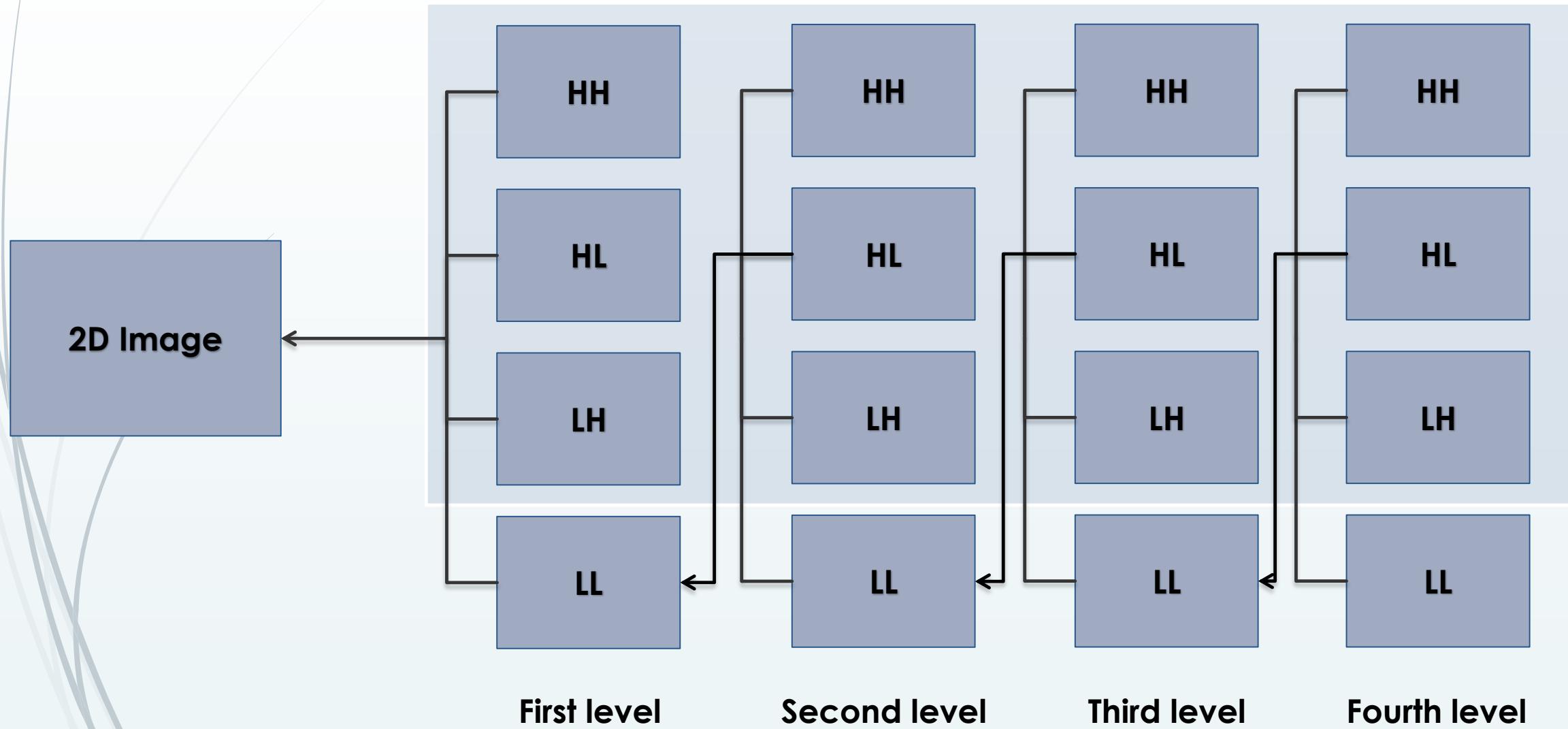
# Local Variance Estimation



# Wiener Filter



# Inverse Wavelet



# Correlation

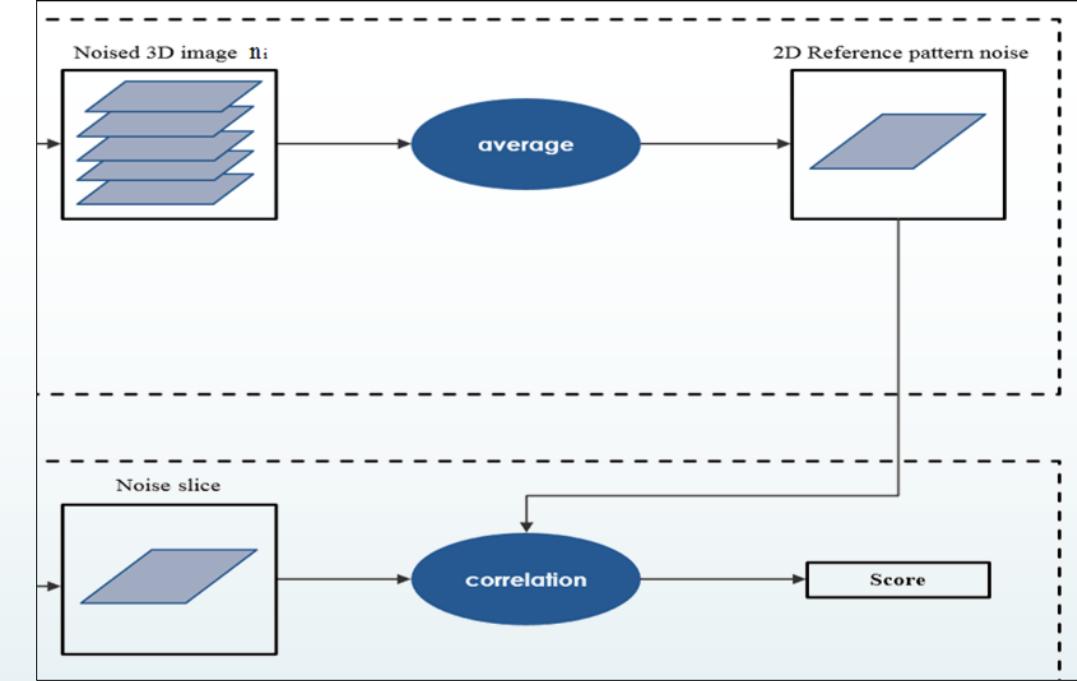
## 3. Decision by correlation

$$\text{corr}(n, RPN) = \frac{(n - \bar{n}) \cdot (RPN - \overline{RPN})}{\|n - \bar{n}\| \|RPN - \overline{RPN}\|} = \text{score}$$

**$n$ :** is the noise component of the tested slice

$$\text{score}_i = \max(\text{score}_1, \text{score}_2, \text{score}_3, \dots, \text{score}_n)$$

**$i$ :** is the identified device



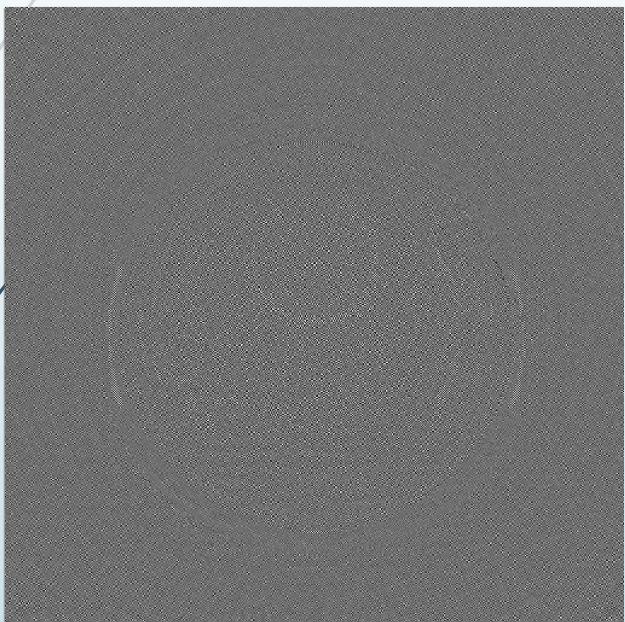
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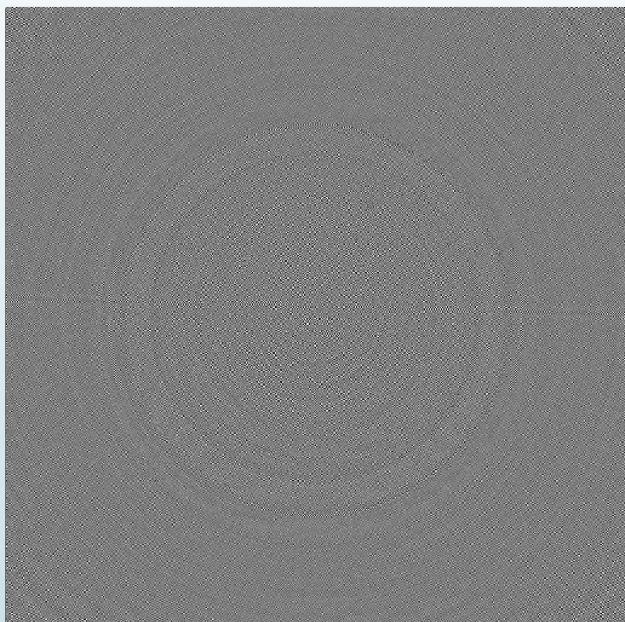
# Experimental images

|                                    | <b>Siemens 1</b> | <b>Siemens 2</b> | <b>GE</b> |
|------------------------------------|------------------|------------------|-----------|
| <b>Content</b>                     | Phantom          | Phantom          | skull     |
| <b>Nb of images</b>                | 3                | 3                | 2         |
| <b>Nb of slices</b>                | 300              | 300              | 200       |
| <b>Size (pixels)</b>               | 512x512          | 512x512          | 512x512   |
| <b>Bits per pixel</b>              | 16               | 16               | 16        |
| <b>Slice thickness</b>             | 3mm              | 3mm              | 3mm       |
| <b>Pixel size</b>                  | 1mm              | 1mm              | 1mm       |
| <b>Nb of slices to compute RPN</b> | 120              | 120              | 120       |
| <b>Nb of tested slices</b>         | 300              | 300              | 300       |

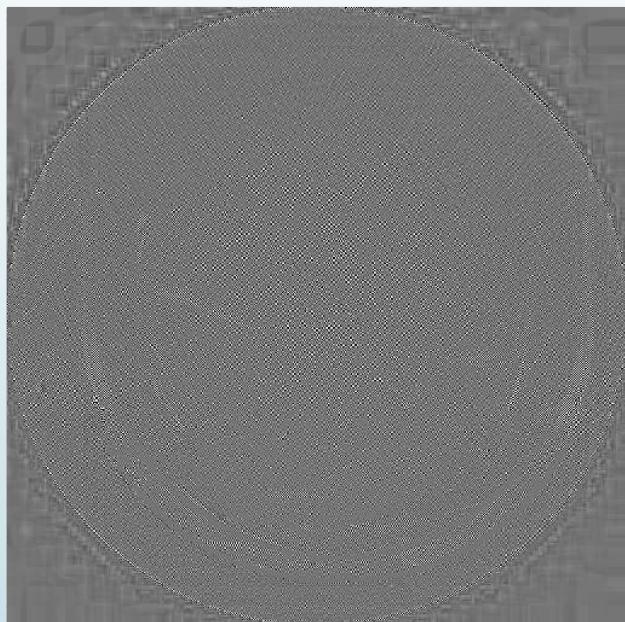
# Results



(a)



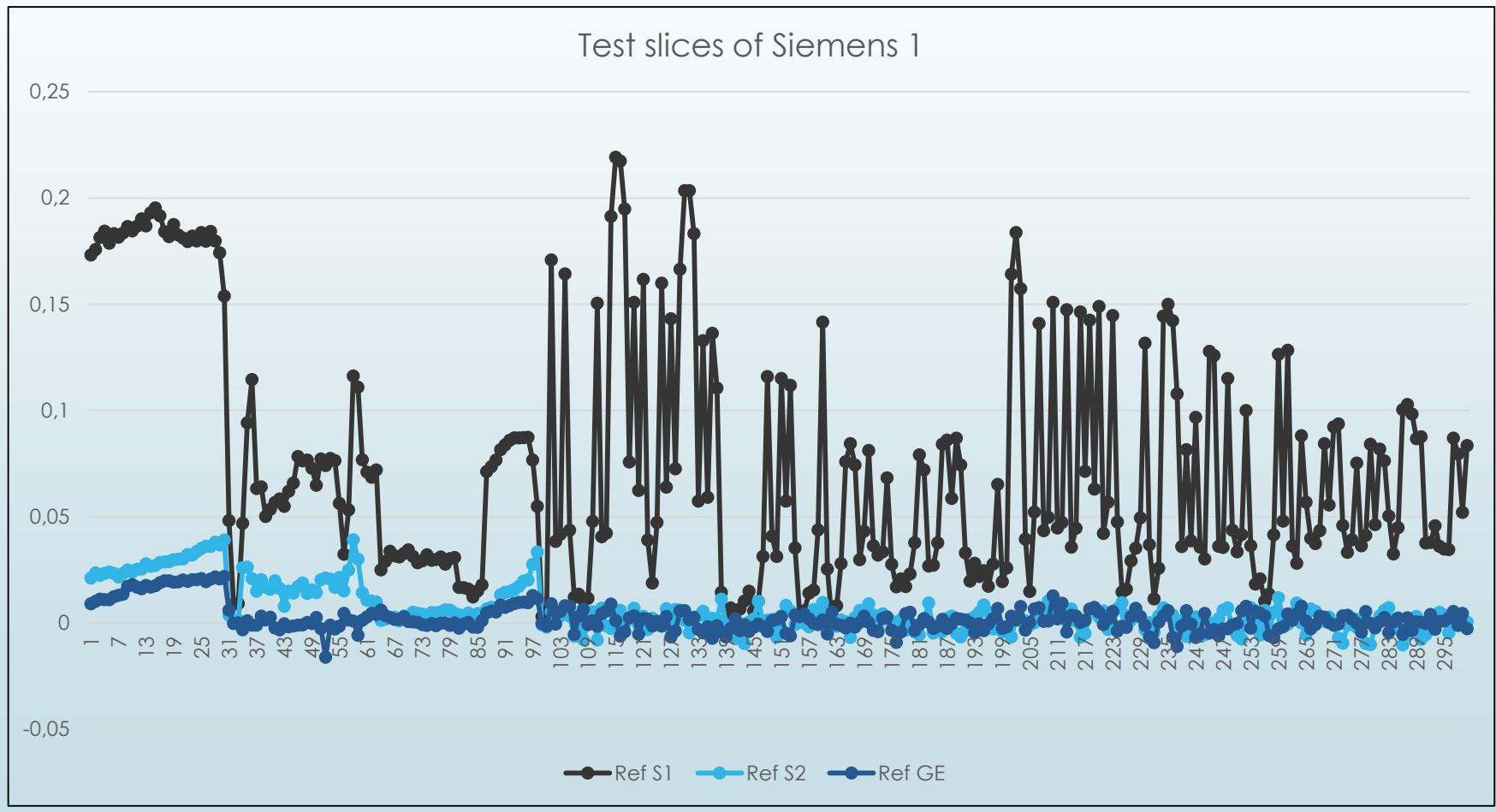
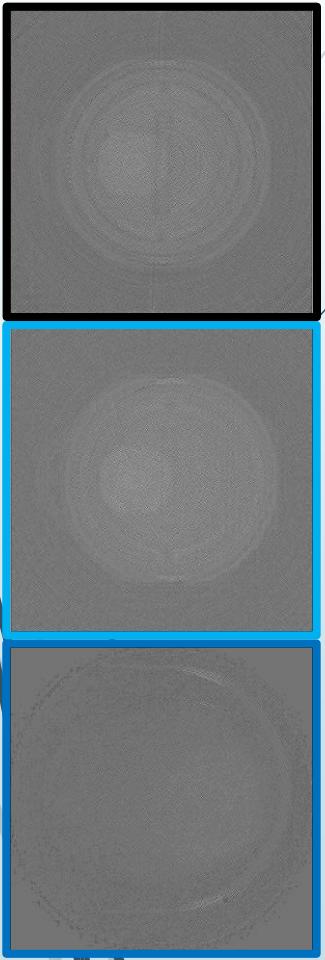
(b)



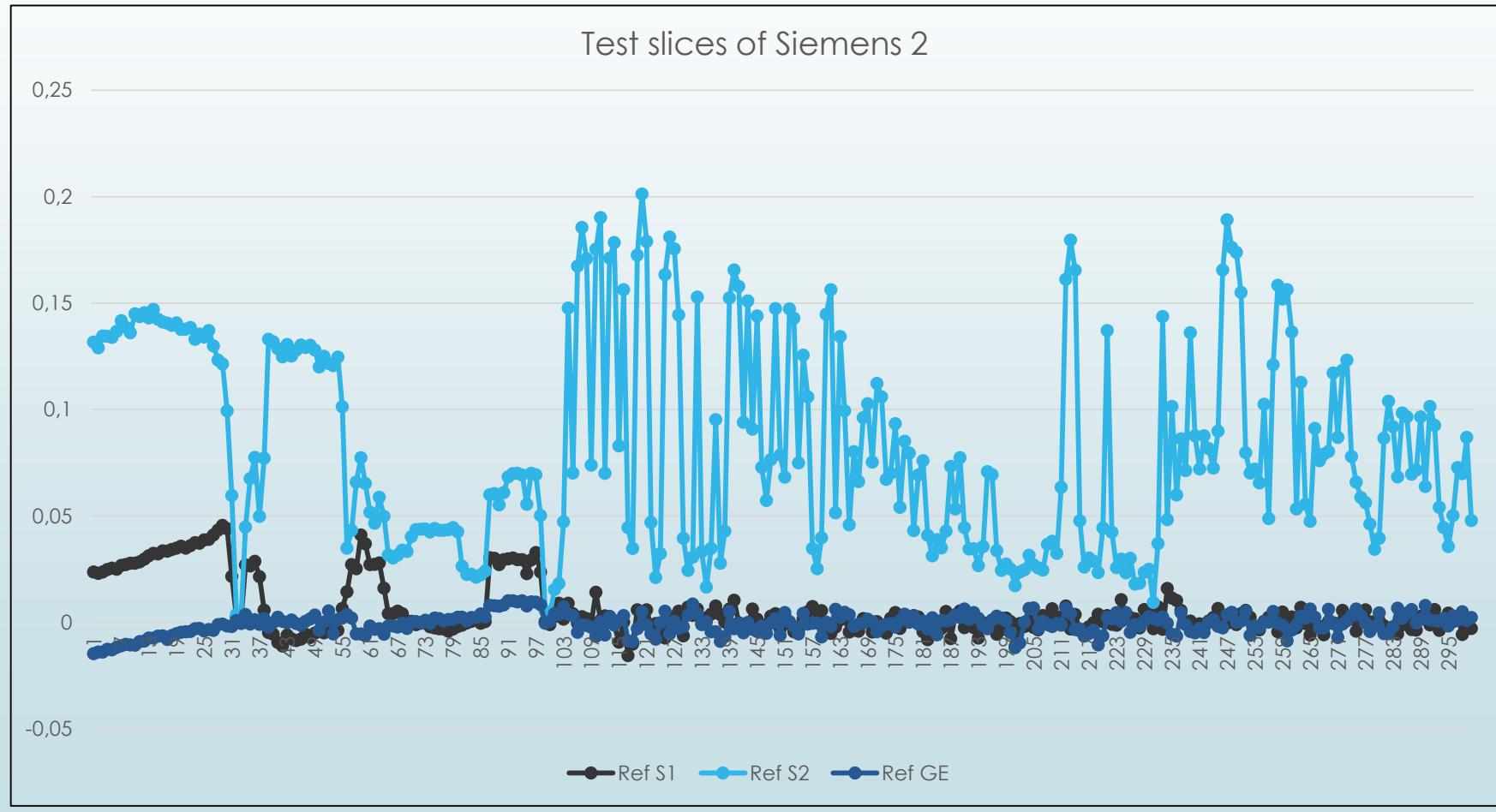
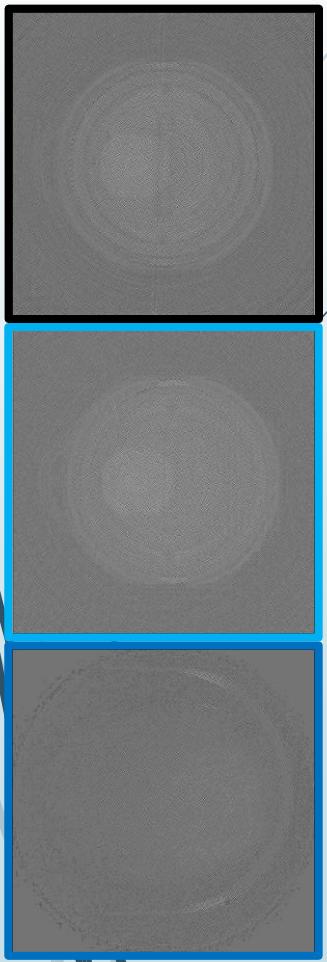
(c)

Reference pattern noise from: a) Siemens device Ref S1, b) Siemens device Ref S2, c) General Electric Ref GE

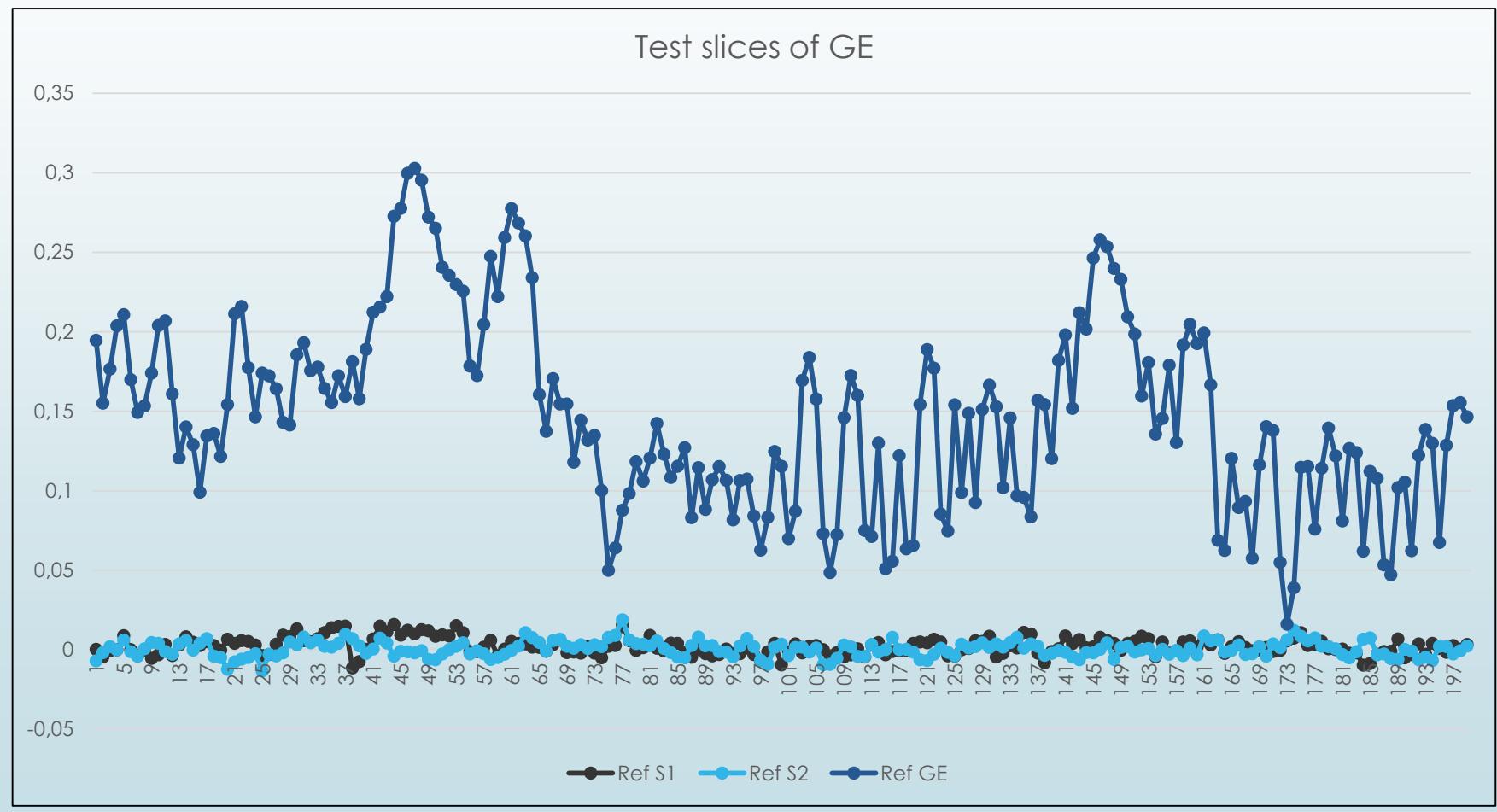
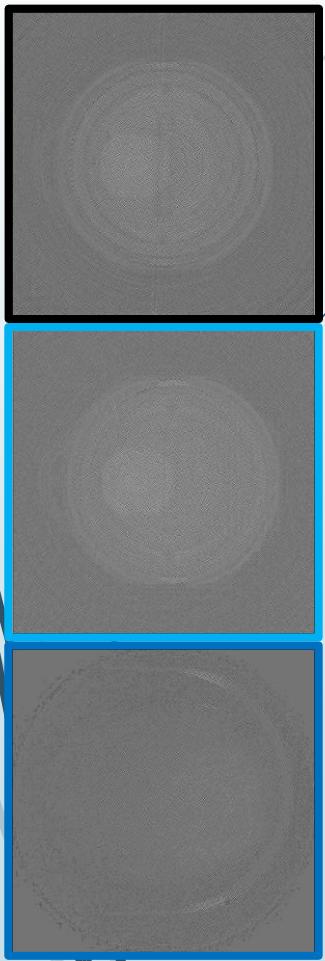
# Results



# Results



# Results



# Identification accuracy

|           | Siemens 1 | Siemens 2 | GE    |
|-----------|-----------|-----------|-------|
| Siemens 1 | 99.3 %    | 0 %       | 0 %   |
| Siemens 2 | 0.7 %     | 100 %     | 0 %   |
| GE        | 0 %       | 0 %       | 100 % |

# Outlines

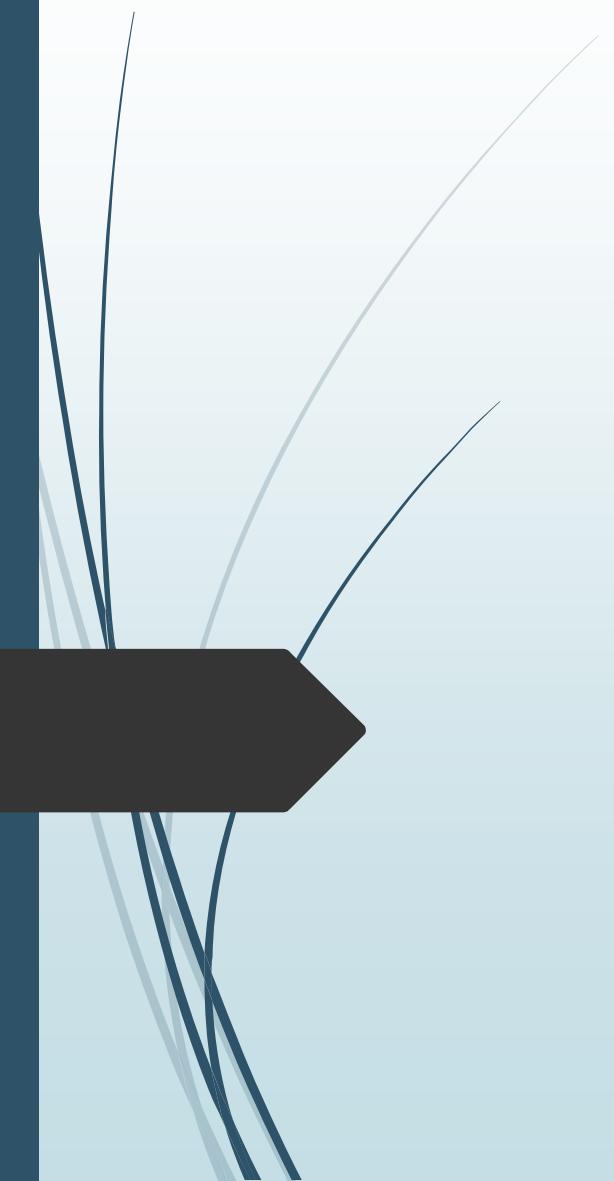
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# Conclusion

- Preliminary results on CT-Scanner identification based on sensor noise analyzing.

# Future work

- Working with more images and more devices
- Generalize the work in 3D
- Analyze the noise model.
- Study the influence of acquisition parameters [Solomon et al. 2013]
- Study the possibility of classifying the images that are acquired by one device but in different acquisition parameters
- Study the influence of image compression on the CT-Scanner identification



Merci de votre attention

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Question?